

5. (Amended)

Q<sup>2</sup>

A product line of negative temperature coefficient thermistors, comprising:  
a first negative temperature thermistor product having a first physical size and having a first resistance defined by a first negative temperature coefficient of resistance versus temperature curve;  
a second negative temperature thermistor product having a second physical size and having a second resistance defined by a second negative temperature coefficient of resistance versus temperature curve, the first physical size the same as the second physical size, the first curve different from the second curve; and  
the first negative temperature coefficient thermistor product being manufactured using deposition of a first metal oxide mixture and the second negative temperature thermistor product being manufactured using deposition of a second metal oxide mixture.

8. (Amended)

Q<sup>3</sup>

A method of manufacturing a thin film negative temperature coefficient thermistor comprising:  
selecting a physical size of the thermistor;  
selecting a negative temperature coefficient of resistance versus temperature curve;  
selecting a mixture of metal film materials to provide a negative temperature coefficient of resistance curve while maintaining the physical size; and  
depositing the mixture of metal film materials on a substrate.

10. (Amended)

Q<sup>4</sup>

The method of claim 8 wherein the mixture is a mixture of manganese oxide and nickel oxide.